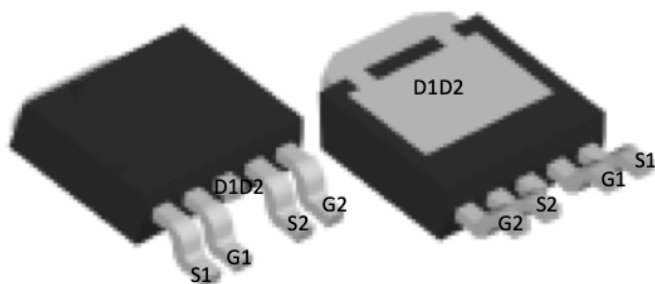
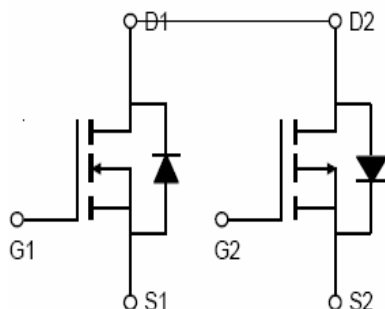


# N-Channel and P-Channel Complementary Power MOSFET


**TO-252-4L**


## Product Summary

### NMOS

- $V_{DS}$  30V
- $I_D$  12A
- $R_{DS(ON)}$ ( at  $V_{GS}=10V$ ) <30mohm
- $R_{DS(ON)}$ ( at  $V_{GS}=4.5V$ ) <45mohm

### PMOS

- $V_{DS}$  -30V
- $I_D$  -8A
- $R_{DS(ON)}$ ( at  $V_{GS}=-10V$ ) <55mohm
- $R_{DS(ON)}$ ( at  $V_{GS}=-4.5V$ ) <80mohm

- 100%  $\nabla V_{DS}$  Tested

## General Description

- Trench Power LV MOSFET technology
- High density cell design for low  $R_{DS(ON)}$
- High Speed switching

## Applications

- Wireless charger
- Load switch
- Power management

### ■ Absolute Maximum Ratings ( $T_A=25^\circ C$ unless otherwise noted)

Parameter	Symbol	N-Channel	P-Channel	Unit
Drain-source Voltage	$V_{DS}$	30	-30	V
Gate-source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V
Drain Current	$I_D$	12	-8	A
Pulsed Drain Current <sup>A</sup>	$I_{DM}$	30	-20	A
Total Power Dissipation	$P_D$	15	15	W
Thermal Resistance Junction-to-Ambient <sup>B</sup>	$R_{\theta JA}$	62.5	62.5	$^\circ C/W$
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55~+150	-55~+150	$^\circ C$

## ■ N-MOS Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=250\mu A$	30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=30V, V_{GS}=0V$			1	$\mu A$
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$			$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.5	2.2	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=5.6A$		20	30	m $\Omega$
		$V_{GS}=4.5V, I_D=5.0A$		30	45	
Diode Forward Voltage	$V_{SD}$	$I_S=5.6A, V_{GS}=0V$			1.2	V
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=15V, V_{GS}=0V, f=1\text{MHz}$		490		pF
Output Capacitance	$C_{oss}$			92		
Reverse Transfer Capacitance	$C_{rss}$			69		
<b>Switching Parameters</b>						
Total Gate Charge	$Q_g$	$V_{GS}=10V, V_{DS}=15V, I_D=5.6A$		5.2		nC
Gate-Source Charge	$Q_{gs}$			0.9		
Gate-Drain Charge	$Q_{gd}$			1.2		
Reverse Recovery Charge	$Q_{rr}$	$I_F=5.6A, di/dt=100A/\mu s$		1.28		ns
Reverse Recovery Time	$t_{rr}$			16.5		
Turn-on Delay Time	$t_{D(on)}$	$V_{GS}=4.5V, V_{DS}=15V, I_D=1A$ $R_{GEN}=3\Omega$		4.5		ns
Turn-on Rise Time	$t_r$			2.5		
Turn-off Delay Time	$t_{D(off)}$			12.8		
Turn-off fall Time	$t_f$			3.5		

A. Pulse Test: Pulse Width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$ .

B.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design, while  $R_{\theta JA}$  is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

## ■ P-MOS Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=-250\mu A$	-30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=-30V, V_{GS}=0V$			-1	$\mu A$
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$			$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1.0	-1.5	-2.4	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=-10V, I_D=-5.0A$		43	55	m $\Omega$
		$V_{GS}=-4.5V, I_D=-4.0A$		55	80	
Diode Forward Voltage	$V_{SD}$	$I_S=-4A, V_{GS}=0V$			-1.2	V
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=-15V, V_{GS}=0V, f=1\text{MHz}$		719		pF
Output Capacitance	$C_{oss}$			441		
Reverse Transfer Capacitance	$C_{rss}$			118		
<b>Switching Parameters</b>						
Total Gate Charge	$Q_g$	$V_{GS}=-10V, V_{DS}=-15V, I_D=-5.1A$		27		nC
Gate-Source Charge	$Q_{gs}$			2.6		
Gate-Drain Charge	$Q_{gd}$			6.6		
Turn-on Delay Time	$t_{D(on)}$	$V_{GS}=-10V, V_{DS}=-15V, I_D=-1A$ $R_{GEN}=6\Omega$		8		ns
Turn-on Rise Time	$t_r$			15		
Turn-off Delay Time	$t_{D(off)}$			77		
Turn-off fall Time	$t_f$			42		

C. Pulse Test: Pulse Width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$ .

D.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design, while  $R_{\theta JA}$  is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

## N-MOS Typical Performance Characteristics

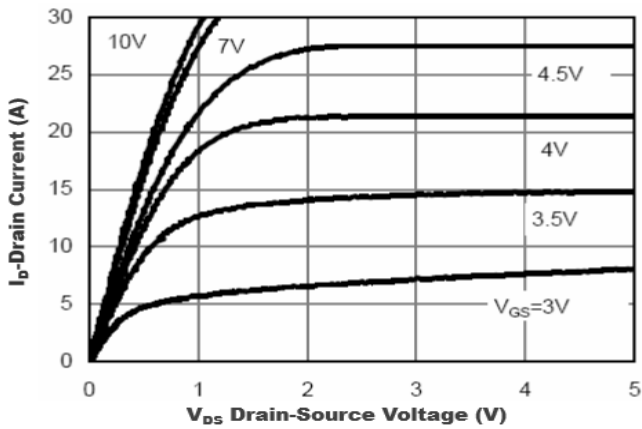


Figure1. Output Characteristics

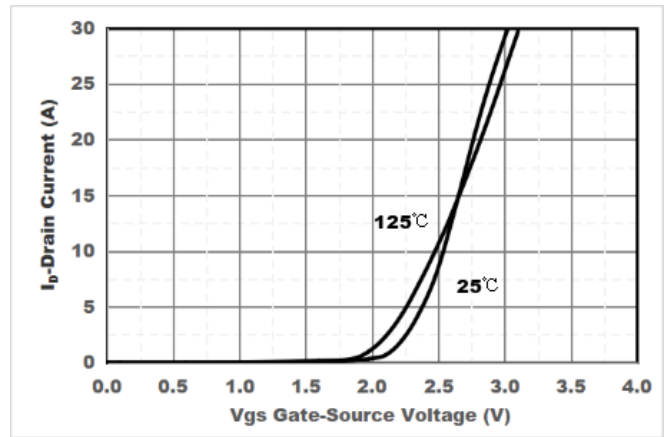


Figure2. Transfer Characteristics

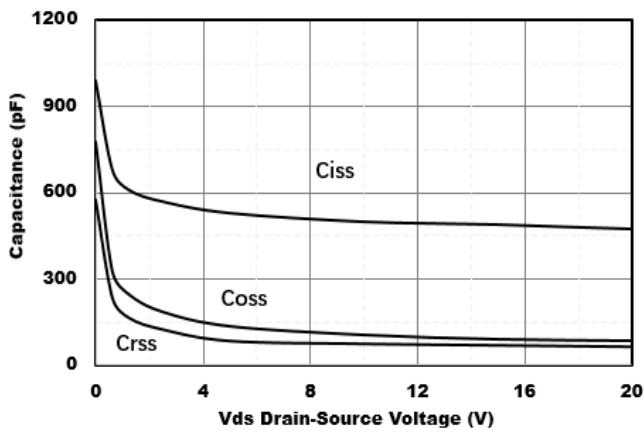


Figure3. Capacitance Characteristics

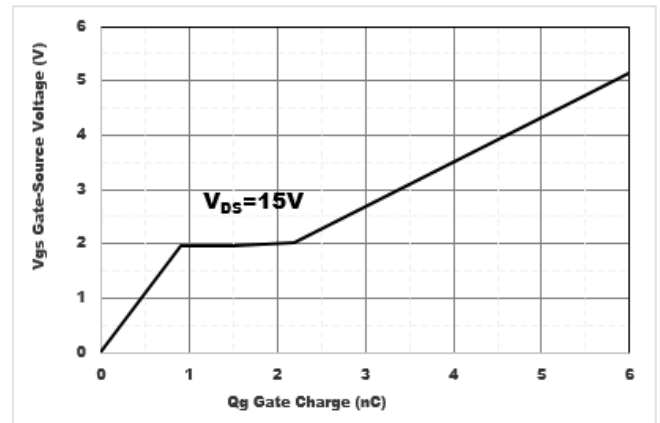


Figure4. Gate Charge

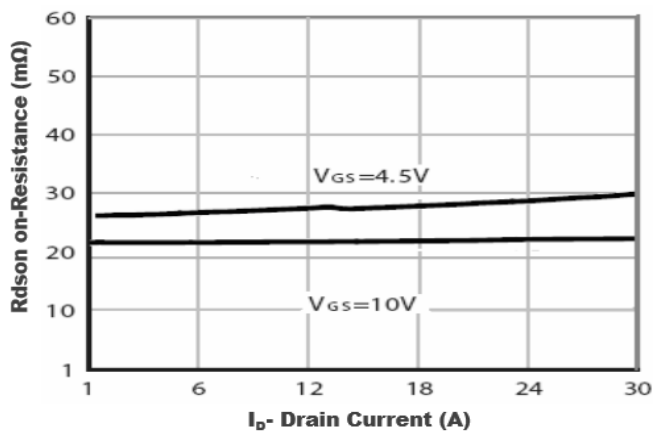


Figure5. Drain-Source on Resistance

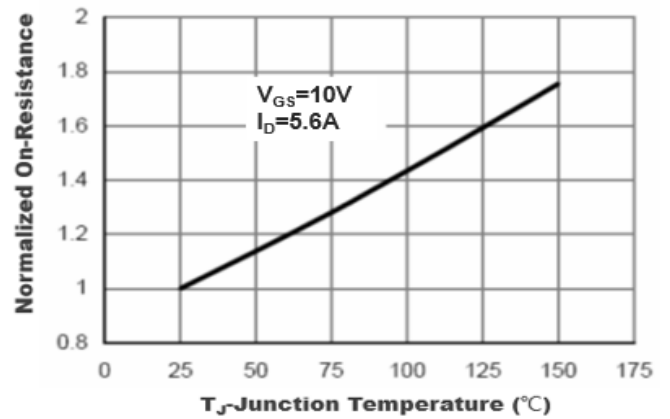


Figure6. Drain-Source on Resistance

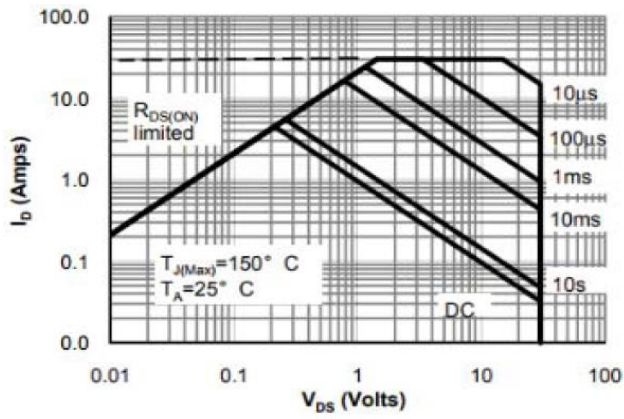


Figure7. Safe Operation Area

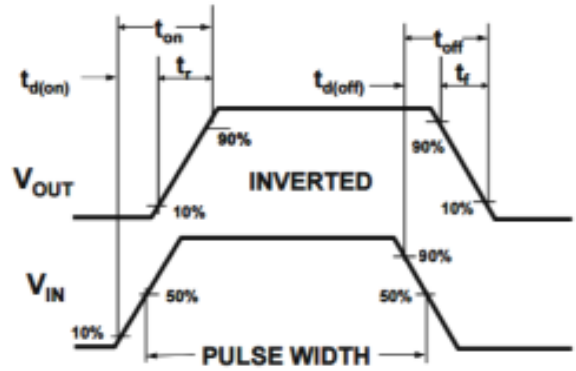


Figure8. Switching wave

## ■ P-MOS Typical Performance Characteristics

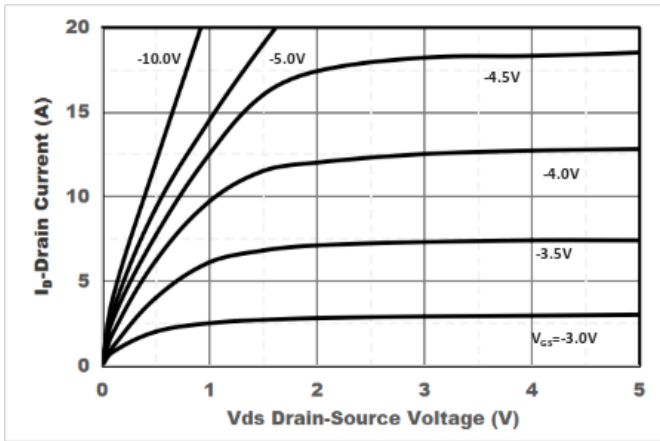


Figure1. Output Characteristics

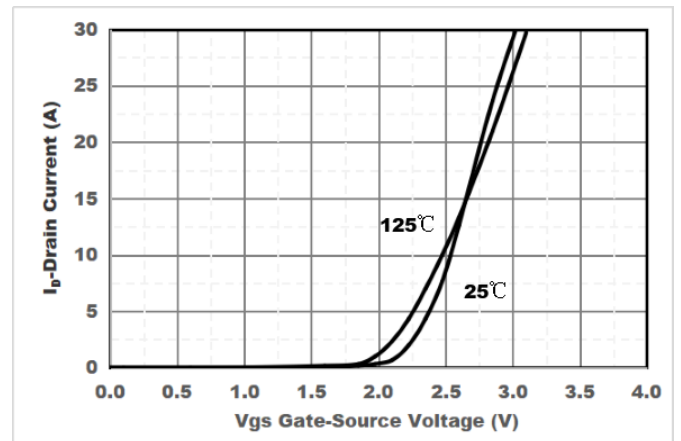


Figure2. Transfer Characteristics

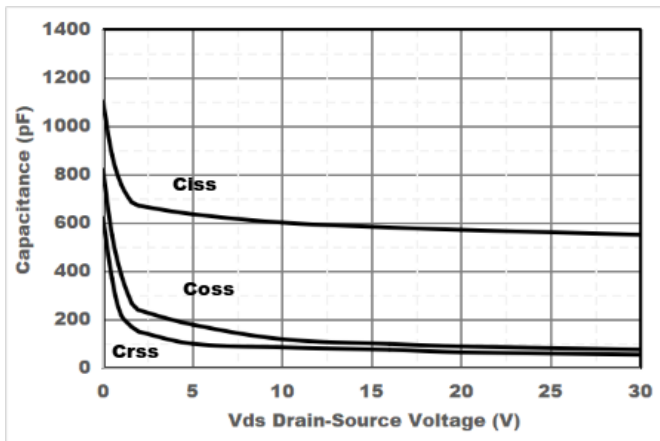


Figure3. Capacitance Characteristics

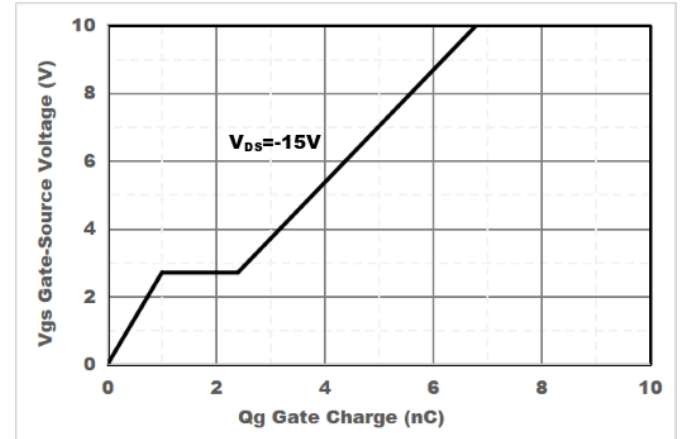


Figure4. Gate Charge

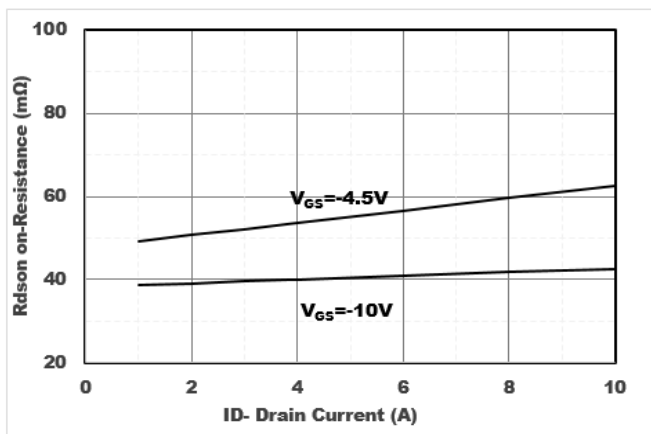


Figure5. Drain-Source on Resistance

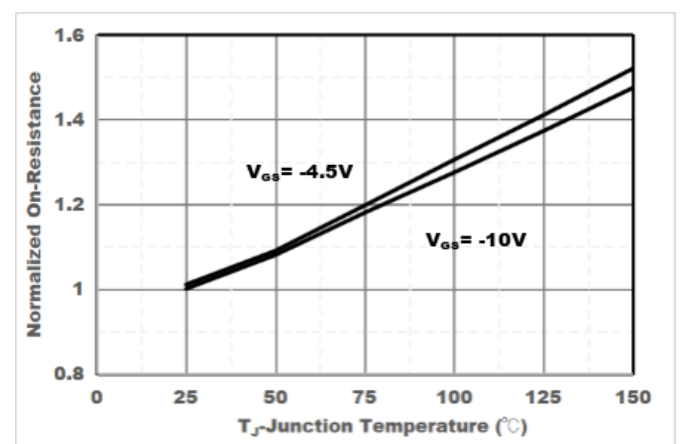


Figure6. Drain-Source on Resistance

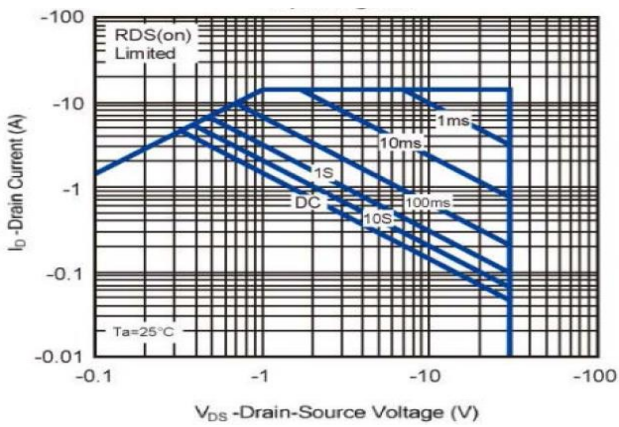


Figure7. Safe Operation Area

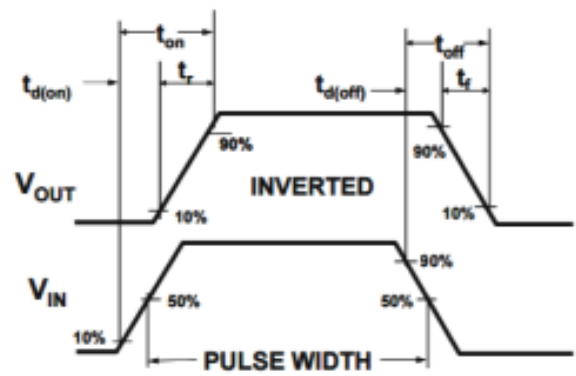


Figure8. Switching wave

■ TO-252-4L Package information

